

SN74ALVCH16260

12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH

WITH 3-STATE OUTPUTS

SCES046 – JULY 1995

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883C, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JEDEC Standard JESD-17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 12-bit to 24-bit multiplexed D-type latch is designed for 2.3-V to 3.6- V_{CC} operation.

The SN74ALVCH16260 is used in applications where two separate datapaths must be multiplexed onto, or demultiplexed from, a single datapath. Typical applications include multiplexing and/or demultiplexing address and data information in microprocessor or bus-interface applications. This device is also useful in memory-interleaving applications.

Three 12-bit I/O ports (A1–A12, 1B1–1B12, and 2B1–2B12) are available for address and/or data transfer. The output-enable ($\overline{OE1B}$, $\overline{OE2B}$, and $\overline{OE A}$) inputs control the bus transceiver functions. The $\overline{OE1B}$ and $\overline{OE2B}$ control signals also allow bank control in the A-to-B direction.

Address and/or data information can be stored using the internal storage latches. The latch-enable (LE1B, LE2B, LEA1B, and LEA2B) inputs are used to control data storage. When the latch-enable input is high, the latch is transparent. When the latch-enable input goes low, the data present at the inputs is latched and remains latched until the latch-enable input is returned high.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16260 is available in TI's shrink small-outline (DL) and thin shrink small-outline (DGG) packages, which provide twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The SN74ALVCH16260 is characterized for operation from –40°C to 85°C.

DGG OR DL PACKAGE (TOP VIEW)

$\overline{OE A}$	1	56	$\overline{OE2B}$
LE1B	2	55	LEA2B
2B3	3	54	2B4
GND	4	53	GND
2B2	5	52	2B5
2B1	6	51	2B6
V_{CC}	7	50	V_{CC}
A1	8	49	2B7
A2	9	48	2B8
A3	10	47	2B9
GND	11	46	GND
A4	12	45	2B10
A5	13	44	2B11
A6	14	43	2B12
A7	15	42	1B12
A8	16	41	1B11
A9	17	40	1B10
GND	18	39	GND
A10	19	38	1B9
A11	20	37	1B8
A12	21	36	1B7
V_{CC}	22	35	V_{CC}
1B1	23	34	1B6
1B2	24	33	1B5
GND	25	32	GND
1B3	26	31	1B4
LE2B	27	30	LEA1B
SEL	28	29	$\overline{OE1B}$



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

EPIC and Widebus are trademarks of Texas Instruments Incorporated.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

Copyright © 1995, Texas Instruments Incorporated

SN74ALVCH16260

12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH

WITH 3-STATE OUTPUTS

SCES046 – JULY 1995

Function Tables

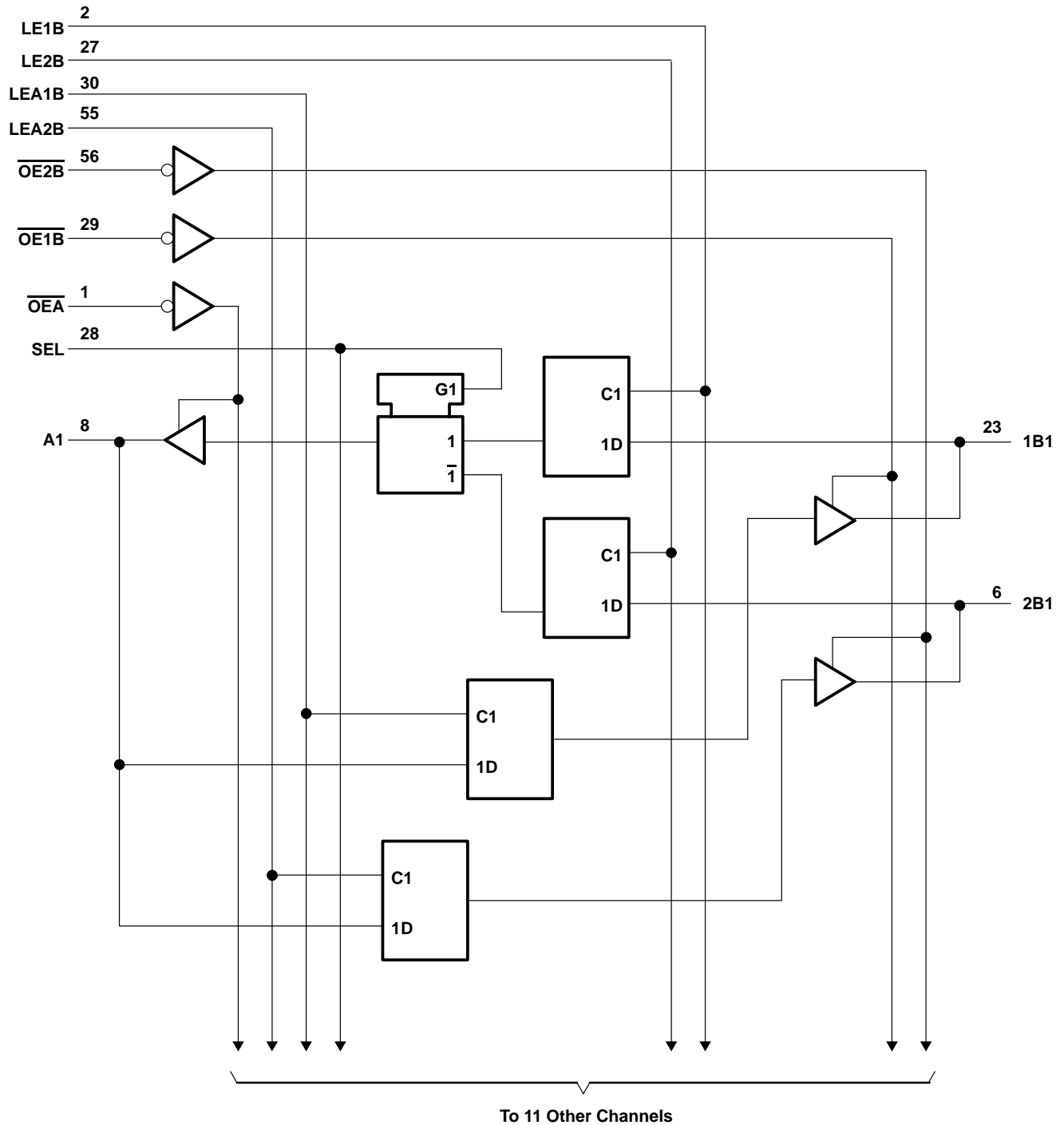
B TO A ($\overline{OE}B = H$)

INPUTS						OUTPUT A
1B	2B	SEL	LE1B	LE2B	$\overline{OE}A$	
H	X	H	H	X	L	H
L	X	H	H	X	L	L
X	X	H	L	X	L	A ₀
X	H	L	X	H	L	H
X	L	L	X	H	L	L
X	X	L	X	L	L	A ₀
X	X	X	X	X	H	Z

A TO B ($\overline{OE}A = H$)

INPUTS					OUTPUTS	
A	LEA1B	LEA2B	$\overline{OE}1B$	$\overline{OE}2B$	1B	2B
H	H	H	L	L	H	H
L	H	H	L	L	L	L
H	H	L	L	L	H	2B ₀
L	H	L	L	L	L	2B ₀
H	L	H	L	L	1B ₀	H
L	L	H	L	L	1B ₀	L
X	L	L	L	L	1B ₀	2B ₀
X	X	X	H	H	Z	Z
X	X	X	L	H	Active	Z
X	X	X	H	L	Z	Active
X	X	X	L	L	Active	Active

logic diagram (positive logic)



SN74ALVCH16260

12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH

WITH 3-STATE OUTPUTS

SCES046 – JULY 1995

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I : Except I/O ports (see Note 1)	–0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Maximum power dissipation at $T_A = 55^\circ\text{C}$ (in still air) (see Note 3): DGG package	1 W
DL package	1.4 W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the *Package Thermal Considerations* application note in the 1994 *ABT Advanced BiCMOS Technology Data Book*, literature number SCBD002B.

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		2.3	3.6	V
V _{IH}	High-level input voltage	V _{CC} = 2.3 V to 2.7 V	1.7		V
		V _{CC} = 2.7 V to 3.6 V	2		
V _{IL}	Low-level input voltage	V _{CC} = 2.3 V to 2.7 V	0.7		V
		V _{CC} = 2.7 V to 3.6 V	0.8		
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 2.3 V	−12		mA
		V _{CC} = 2.7 V	−12		
		V _{CC} = 3 V	−24		
I _{OL}	Low-level output current	V _{CC} = 2.3 V	12		mA
		V _{CC} = 2.7 V	12		
		V _{CC} = 3 V	24		
Δt/Δv	Input transition rise or fall rate		0	10	ns/V
T _A	Operating free-air temperature		−40	85	°C

NOTE 4: Unused control inputs must be held high or low to prevent them from floating.

SN74ALVCH16260
12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH
WITH 3-STATE OUTPUTS

SCES046 – JULY 1995

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC} [†]	MIN	TYP [‡]	MAX	UNIT
V _{OH}	I _{OH} = −100 μA		MIN to MAX	V _{CC} − 0.2			V
	I _{OH} = −6 mA, V _{IH} = 1.7 V		2.3 V	2			
	I _{OH} = −12 mA	V _{IH} = 1.7 V	2.3 V	1.7			
		V _{IH} = 2 V	2.7 V	2.2			
		V _{IH} = 2 V	3 V	2.4			
	I _{OH} = −24 mA, V _{IH} = 2 V		3 V	2			
V _{OL}	I _{OL} = 100 μA		MIN to MAX			0.2	V
	I _{OL} = 6 mA, V _{IL} = 0.7 V		2.3 V			0.4	
	I _{OL} = 12 mA	V _{IL} = 0.7 V	2.3 V			0.7	
		V _{IL} = 0.8 V	2.7 V			0.4	
	I _{OL} = 24 mA, V _{IL} = 0.8 V		3 V			0.55	
I _I	V _I = V _{CC} or GND		3.6 V			±5	μA
I _I (hold)	V _I = 0.7 V		2.3 V	45			μA
	V _I = 1.7 V			−45			
	V _I = 0.8 V		3 V	75			
	V _I = 2 V			−75			
	V _I = 0 to 3.6 V		3.6 V			±500	
I _{OZ} [§]	V _O = V _{CC} or GND		3.6 V			±10	μA
I _{CC}	V _I = V _{CC} or GND, I _O = 0		3.6 V			40	μA
ΔI _{CC}	One input at V _{CC} − 0.6 V, Other inputs at V _{CC} or GND		3 V to 3.6 V			750	μA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3.5			pF
C _{io}	A or B ports	V _O = V _{CC} or GND	3.3 V	9			pF

[†] For conditions shown as MIN or MAX, use the appropriate values under recommended operating conditions.

[‡] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[§] For I/O ports, the parameter I_{OZ} includes the input leakage current.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	
t _w	Pulse duration, LE1B, LE2B, LEA1B, or LEA2B high	3.3		3.3		3.3		ns
t _{su}	Setup time, data before LE1B, LE2B, LEA1B, or LEA2B	1.4		1.1		1.1		ns
t _h	Hold time, data after LE1B, LE2B, LEA1B, or LEA2B	1.6		1.9		1.5		ns



SN74ALVCH16260
12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH
WITH 3-STATE OUTPUTS

SCES046 – JULY 1995

switching characteristics over recommended operating free-air temperature range, $C_L = 50$ pF
(unless otherwise noted) (see Figures 1 and 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 2.5\text{ V}$ $\pm 0.2\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V}$ $\pm 0.3\text{ V}$		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
t_{pd}	A or B	B or A	1.2	6	5.1		1.2	4.3	ns
	LE	A or B	1	6.2	5.2		1	4.4	
	SEL	A	1.2	7.5	6.6		1.1	5.6	
t_{en}	\overline{OE}	A or B	1	7.2	6.4		1	5.4	ns
t_{dis}	\overline{OE}	A or B	1.7	5.9	5		1.3	4.6	ns

operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER			TEST CONDITIONS	$V_{CC} = 2.5\text{ V}$ $\pm 0.2\text{ V}$	$V_{CC} = 3.3\text{ V}$ $\pm 0.3\text{ V}$	UNIT
				TYP	TYP	
C_{pd}	Power dissipation capacitance	Outputs enabled	$C_L = 50\text{ pF}, f = 10\text{ MHz}$	87	120	pF
		Outputs disabled		80.5	118	

SN74ALVCH16260

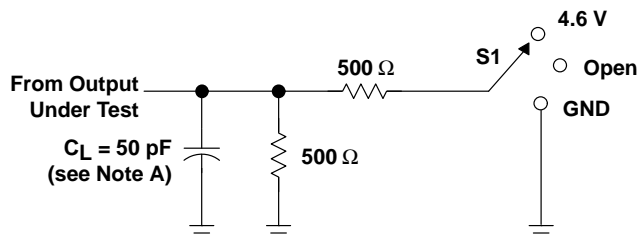
12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH

WITH 3-STATE OUTPUTS

SCES046 – JULY 1995

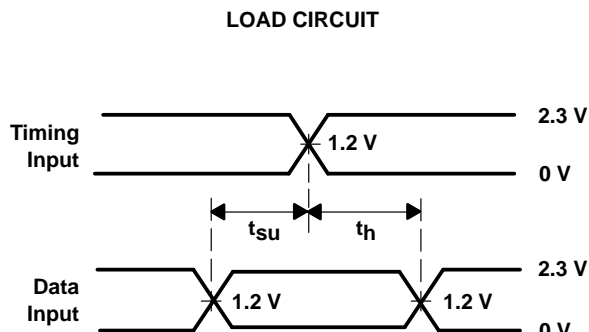
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

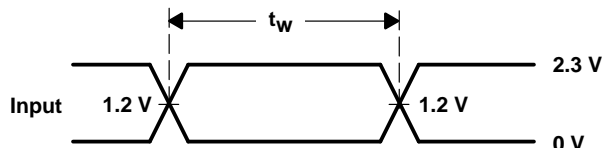


LOAD CIRCUIT

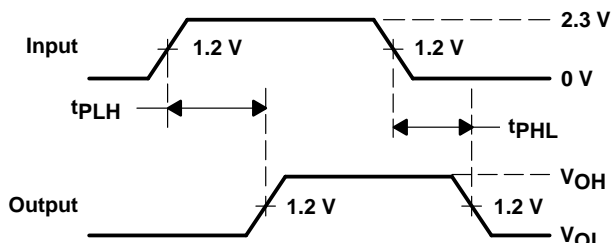
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	4.6 V
t_{PHZ}/t_{PZH}	GND



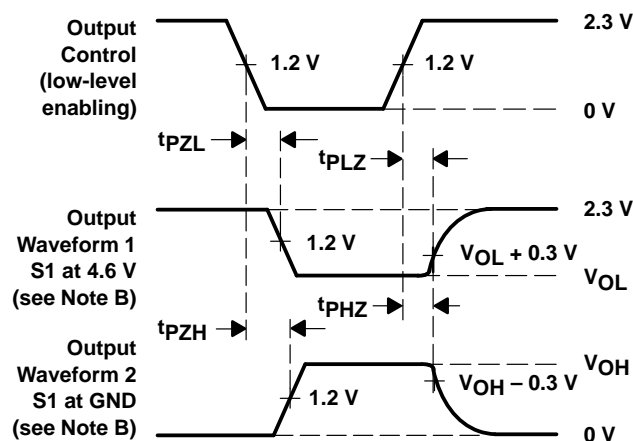
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

SN74ALVCH16260

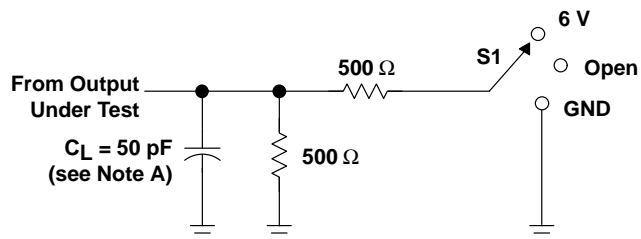
12-BIT TO 24-BIT MULTIPLEXED D-TYPE LATCH

WITH 3-STATE OUTPUTS

SCES046 – JULY 1995

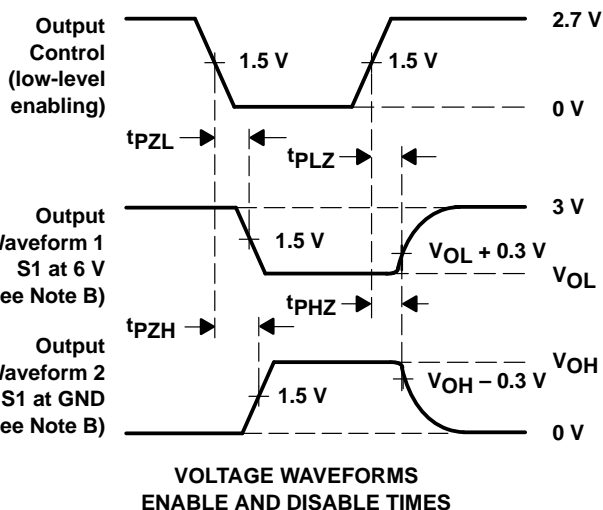
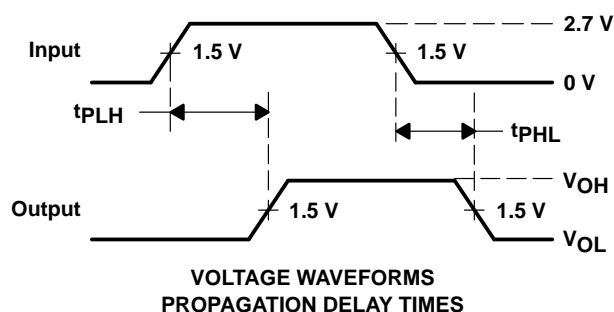
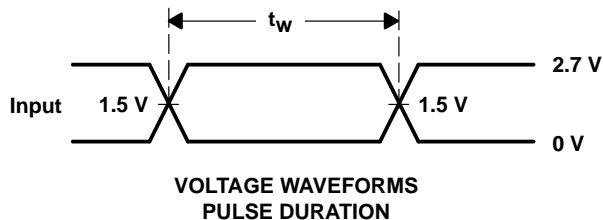
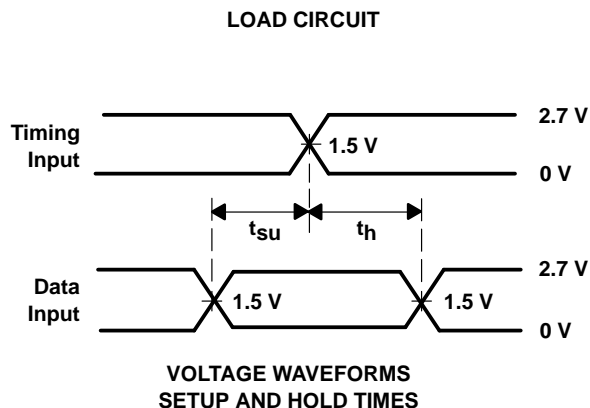
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$



LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2.5\text{ ns}$, $t_f \leq 2.5\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.